



PATENT APPLICATION *AF#*

IN THE U.S. PATENT AND TRADEMARK OFFICE

July 22, 2004 *JFW*

Applicants : Junzo SUNAMOTO et al  
For : HIGH PURITY POLYSACCHARIDE CONTAINING A  
HYDROPHOBIC GROUP AND PROCESS FOR PRODUCING IT  
Serial No. : 10/091 992 Group: 1623  
Confirmation No.: 8077  
Filed : March 6, 2002 Examiner: Lewis  
Atty. Docket No.: Yanagihara Case 49A  
Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**PETITION FOR TIME EXTENSION, AND CERTIFICATE OF MAILING**

Sir:

A Notice of Appeal is enclosed.

Pursuant to 37 CFR 1.136(a), please extend the shortened  
period for response by two months. The extension fee is:

[X] \$420.00 (37 CFR 1.17)

A check for \$750.00 is enclosed to cover fees.

If this Petition is not timely received, please extend the  
shortened period an additional month. Please credit any over-  
payment, or charge any additional fee required by this  
Petition, to Deposit Account No. 06-1382. A duplicate of this  
Petition is enclosed.

Respectfully submitted,

IN DUPLICATE

TFC/smd

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Reg. No. 22 724  
Reg. No. 32 549  
Reg. No. 36 589  
Reg. No. 40 694  
Reg. No. 36 328  
Reg. No. 53 685  
Reg. No. 43 977  
Reg. No. 24 949

07/27/2004 JBALINAN 00000018 10091992

01 FC:1252

420.00 OP

Encl: Check (\$750)  
Notice of Appeal dated July 22, 2004

**CERTIFICATE OF MAILING**

I hereby certify that this correspondence is being  
deposited with the United States Postal Service as first class  
mail in an envelope addressed to: Commissioner for Patents,  
P.O. Box 1450, Alexandria, VA 22313-1450 on July 22, 2004.

181.10/03

*Terryence F. Chapman*  
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